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ABSTRACT OF THE DISCLOSURE

B A scanned-stylus atomic force microscope (AFM) employing  
the optical lever technique, and method of operating the same.  
The AFM of the invention includes a light source and a scanned  
optical assembly which guides <sup>a</sup> light ~~beam~~ emitted from the  
B ~~laser~~ <sup>light</sup> source onto a point on ~~said~~ <sup>a</sup> cantilever during scanning  
B thereof. A moving ~~laser~~ <sup>light</sup> beam is thus created which will  
automatically track the movement of the cantilever during  
scanning. The invention also allows the ~~laser~~ <sup>light</sup> beam to be used  
B to measure, calibrate or correct the motion of the scanning  
mechanism, and further allows viewing of the sample and  
cantilever using an optical microscope.

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